

RoHS

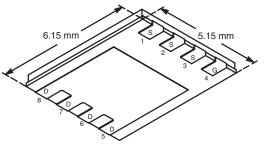
COMPLIANT

HALOGEN FREE

Vishay Siliconix

N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{a, e}	Q _g (Typ.)		
40	0.019 at V _{GS} = 10 V	21	5.8 nC		
	0.0225 at V_{GS} = 4.5 V	19.6	5.6 110		
PowerPAK SO-8					



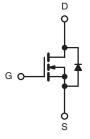
Bottom View

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET[®] Power MOSFET
- 100 % $\rm R_{g}$ and UIS Tested
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

- POL
- Synchronous Rectification



Ordering Information: SiR836DP-T1-GE3 (Lead (Pb)-free and Halogen-free)

N-Channel MOSFET

ABSOLUTE MAXIMUM RATIN	IGS T _A = 25 °C,	unless otherw	vise noted		
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	40	V	
Gate-Source Voltage		V _{GS}	± 20	v	
	T _C = 25 °C		21		
Continuous Drain Current (T_{1} = 150 °C)	T _C = 70 °C		17		
	T _A = 25 °C		10.6 ^{b, c}		
	T _A = 70 °C		8.5 ^{b, c}	Α	
Pulsed Drain Current		I _{DM}	50	A	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	14		
Continuous Source-Drain Diode Current	T _A = 25 °C	'S	3.5 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	10		
Avalanche Energy L = 0.1 mH		E _{AS}	5	mJ	
	T _C = 25 °C		15.6		
Maximum Power Dissipation	T _C = 70 °C	P _D	10	w	
Maximum Power Dissipation	T _A = 25 °C		3.9 ^{b, c}	~~~~	
	T _A = 70 °C	1	2.5 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	0 °	
Soldering Recommendations (Peak Temperations		260			

THEDMAL DESIGTANCE DATINGS

Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	27	32	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	6.4	8.0		

Notes:

a. Based on $T_{\rm C}$ = 25 °C.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under Steady State conditions is 70 °C/W.

e. Package limited.

g. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

f. See Solder Profile (www.vishay.com/ppg?73257). The PowerPAK SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static					•		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 1 mA$	40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L 050		50		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	- Ι _D = 250 μΑ		- 4.8			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.2		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ	
		$V_{DS} = 40 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 ^{\circ}\text{C}$			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 V, V_{GS} = 10 V$	30			Α	
	R	V _{GS} = 10 V, I _D = 10 A		0.015	0.019	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 7 A		0.018	0.0225		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 10 A		35		S	
Dynamic ^b							
Input Capacitance	C _{iss}			600			
Output Capacitance	C _{oss}	V _{DS} = 20 V, V _{GS} = 0 V, f = 1 MHz		100		pF	
Reverse Transfer Capacitance	C _{rss}			50			
·		$V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 10 \text{ A}$		11.8	18	nC	
Total Gate Charge				5.8	9		
Gate-Source Charge	Q _{gs}	$V_{DS} = 20 \text{ V}, \text{ V}_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 10 \text{ A}$		1.6			
Gate-Drain Charge	Q _{gd}			2.1			
Gate Resistance	Rg	f = 1 MHz	0.5	2.4	4.8	Ω	
Turn-On Delay Time	t _{d(on)}			14	28	- ns	
Rise Time	t _r	V_{DD} = 20 V, R_L = 2 Ω		19	38		
Turn-Off Delay Time	t _{d(off)}	$\rm I_D \cong 10$ A, $\rm V_{GEN}$ = 4.5 V, $\rm R_g$ = 1 Ω		17	34		
Fall Time	t _f			11	22		
Turn-On Delay Time	t _{d(on)}			8	16		
Rise Time	t _r	V_{DD} = 20 V, R_L = 2 Ω		13	26		
Turn-Off Delay Time	t _{d(off)}	$\text{I}_\text{D}\cong$ 10 A, V_GEN = 10 V, R_g = 1 Ω		15	30		
Fall Time	t _f			9	18		
Drain-Source Body Diode Characterist	cs						
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			14	•	
Pulse Diode Forward Current ^a	I _{SM}				50	A	
Body Diode Voltage	V _{SD}	I _S = 3 A		0.77	1.1	V	
Body Diode Reverse Recovery Time	t _{rr}			15	30	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	-		7.5	15	nC	
Reverse Recovery Fall Time	ta	— I _F = 5 A, dl/dt = 100 A/μs, T _J = 25 °C		8			
Reverse Recovery Rise Time	t _b	1		7		ns	

Notes:

a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

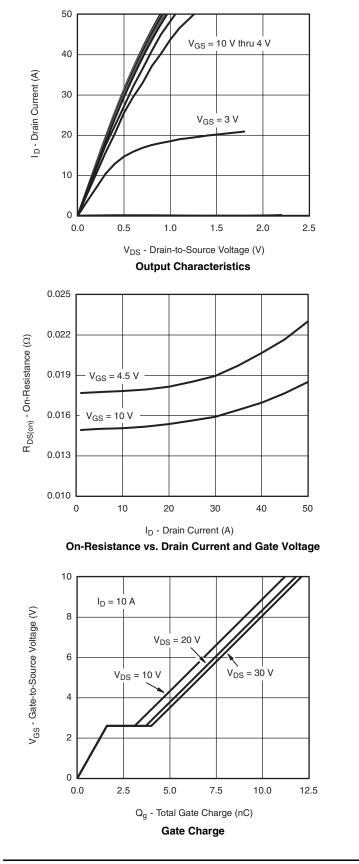
b. Guaranteed by design, not subject to production testing.

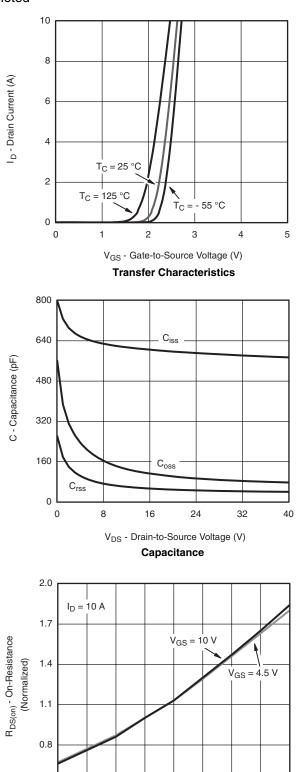
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





0.5

- 50

- 25

0

25

50

T_J - Junction Temperature (°C) On-Resistance vs. Junction Temperature

75

100

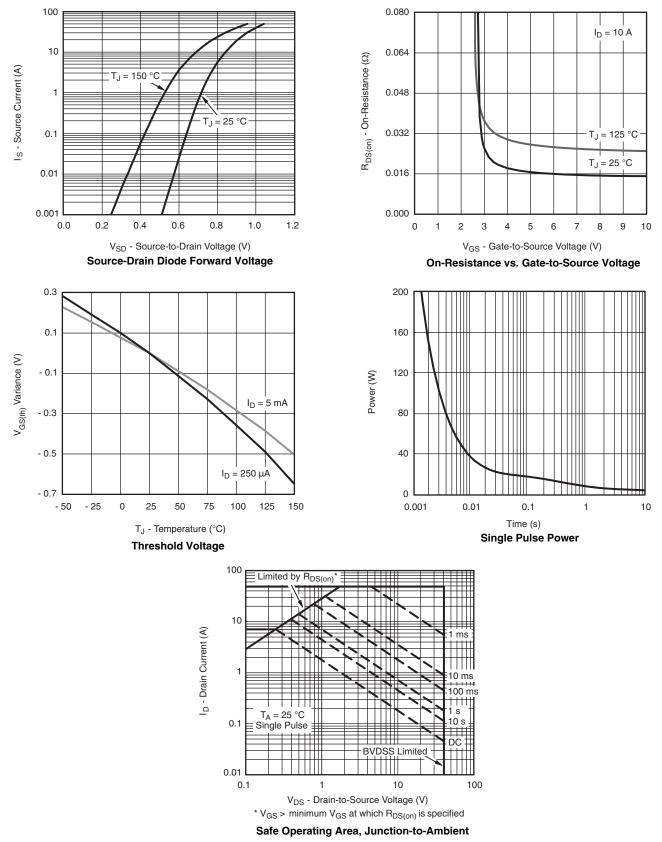
150

125

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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

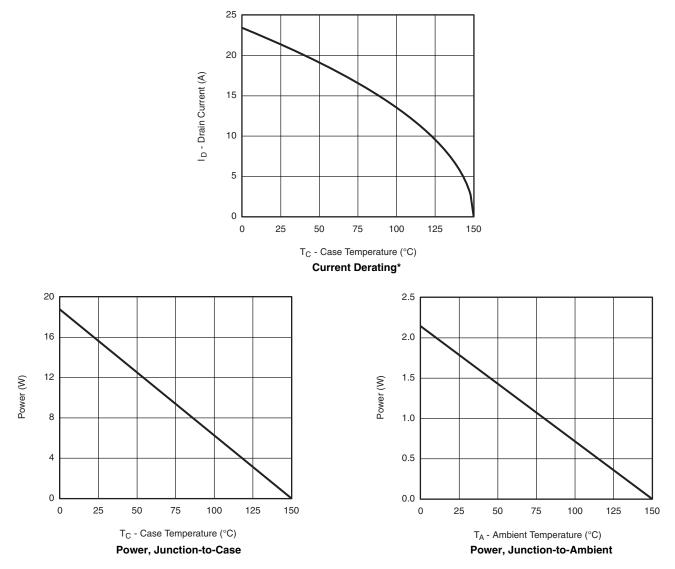


New Product



SiR836DP Vishay Siliconix

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

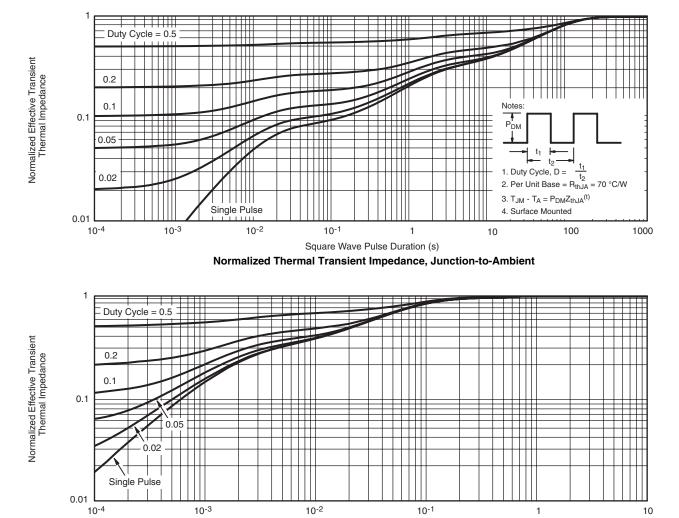


* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Square Wave Pulse Duration (s) Normalized Thermal Transient Impedance, Junction-to-Case

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see www.vishay.com/ppg?65543.



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